

Supporting Information

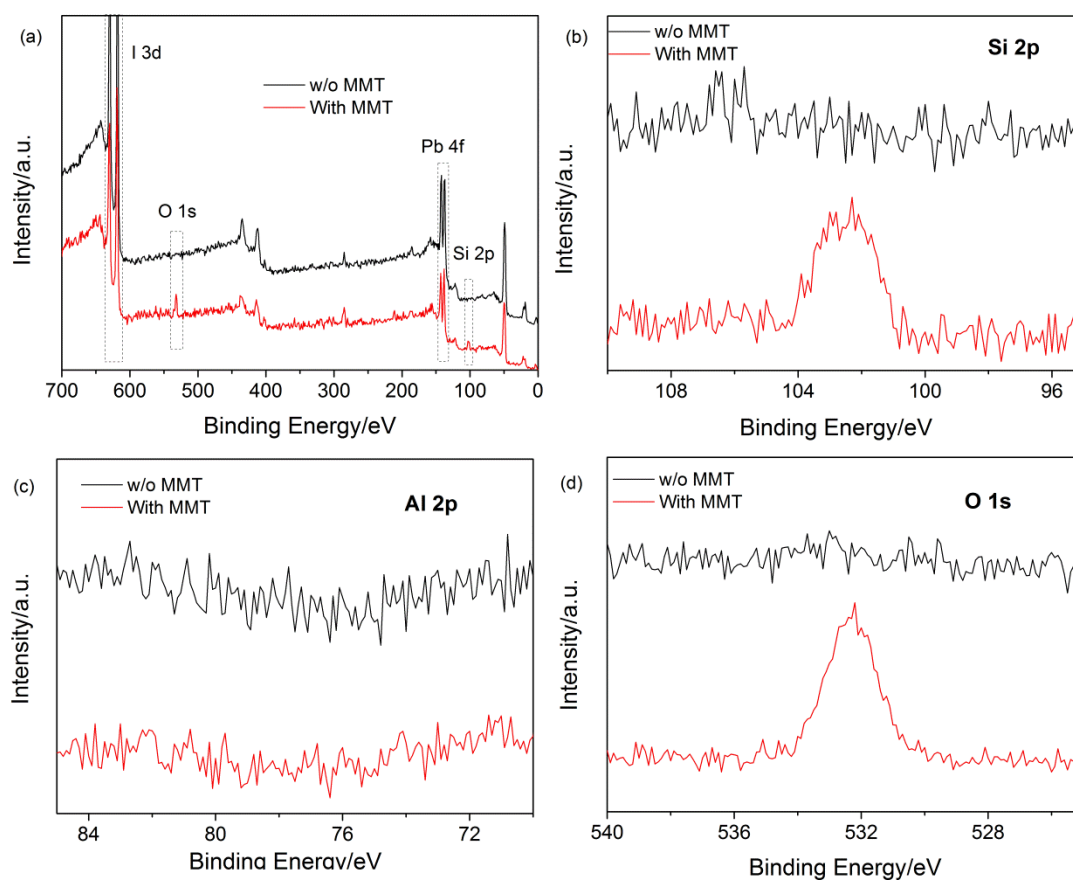


Fig. S1 (a) Overall XPS spectra, (b) XPS spectra of Si, (c) XPS spectra of Al, (d) XPS spectra of O.

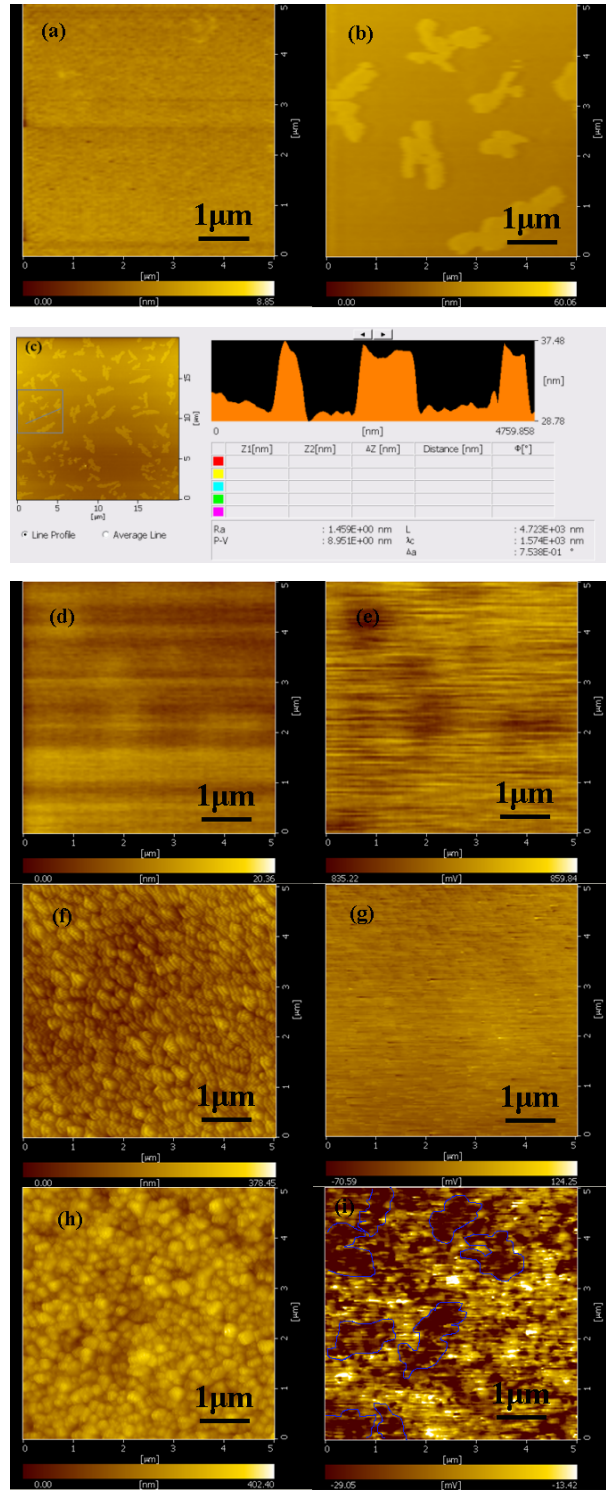


Fig. S2 AFM images of (a) a Si slice and (b) a Si slice covered by MMT, (c) the line profile of the Si slice covered by MMT, (d) TOPO phase and (e) potential phase of Si slice covered by MMT, (f) TOPO phase and (g) potential phase of Si slice covered by perovskite, (h) TOPO phase and (i) potential phase of Si slice covered by perovskite with MMT.

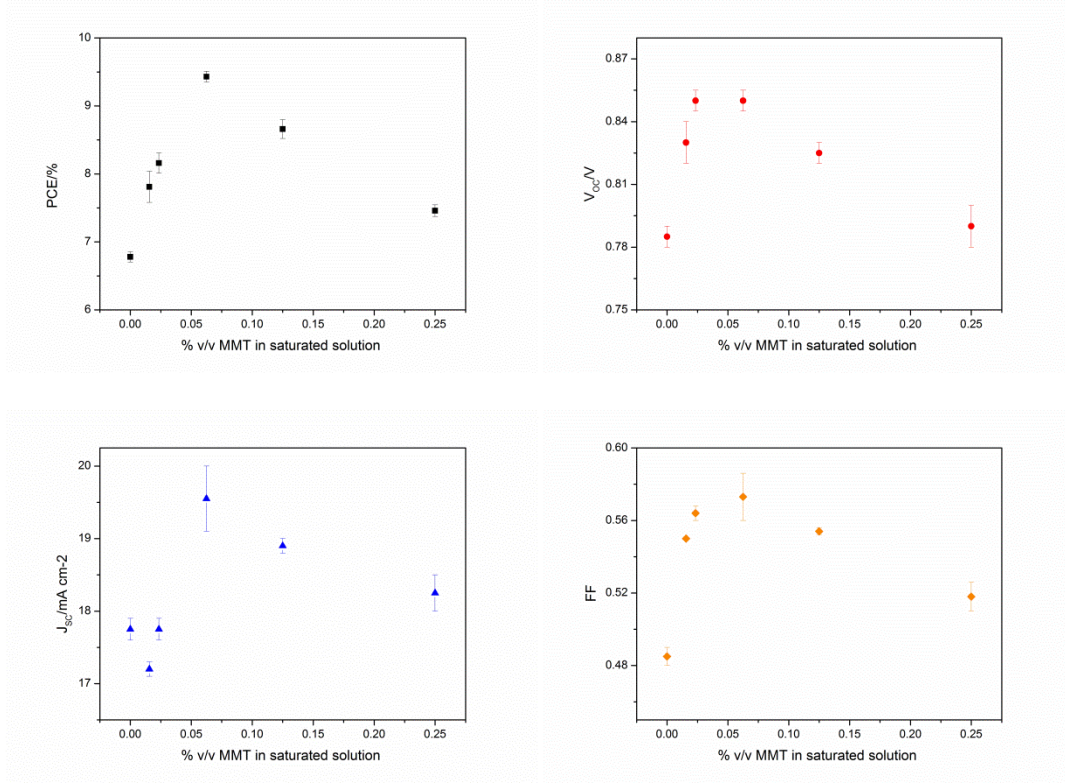


Fig. S3. PCE, V_{oc} , J_{sc} and FF data followed the content of MMT dispersion from 0.00% to 25% v/v. The percentage is accorded by the saturated dispersion.